

FIG. 3

OBLON, SPIVAK, ET AL DOCKET #: 241713US2SRD INV: Hideo TSUCHIYA, et al. SHEET 3 OF 9

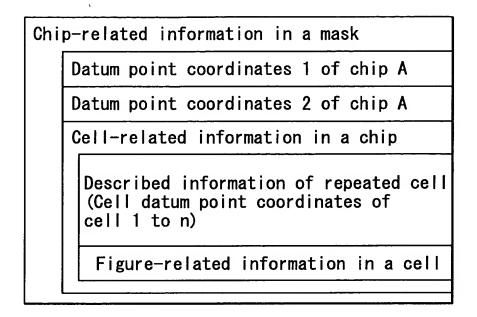


FIG. 4

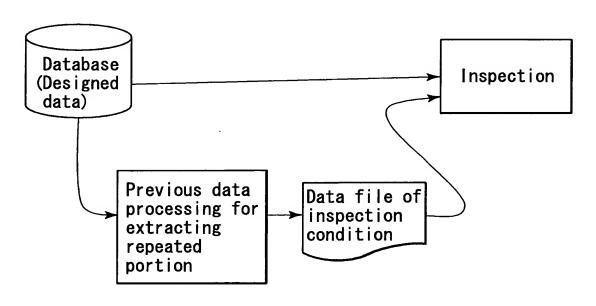


FIG. 5

```
Inspection data item:
Threshold level of defect or not
Discrimination condition a:
Discrimination condition b:
Discrimination condition c:

Illumination method of
transmitted/reflected light:
Magnification mode of optics in inspection
Alignment-related information
::::
Inspection mode of die-to-die combined
with die-to-database (ON/OFF)
Start point coordinates of die 1(x1, y1):
Finish point coordinates of die 2(x3, y3):
Finish point coordinates of die 2(x4, y4):
```

FIG. 6

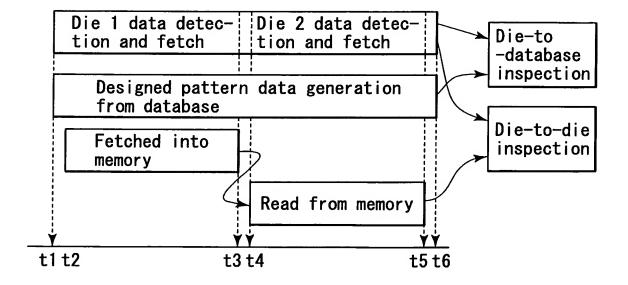
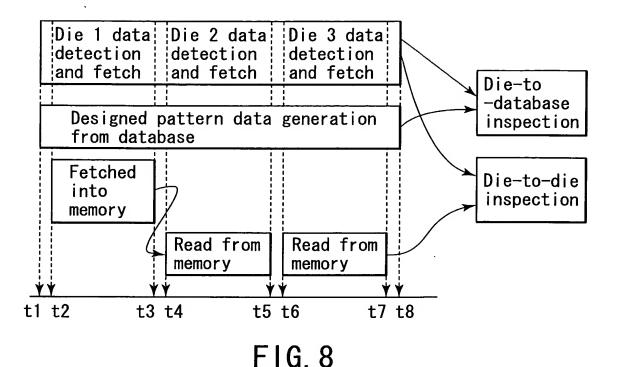


FIG. 7



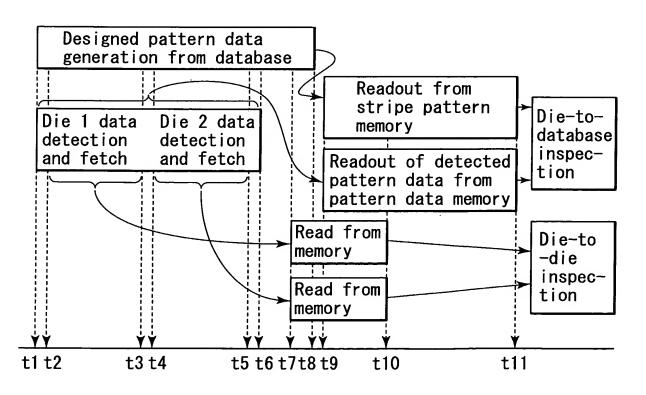


FIG. 9

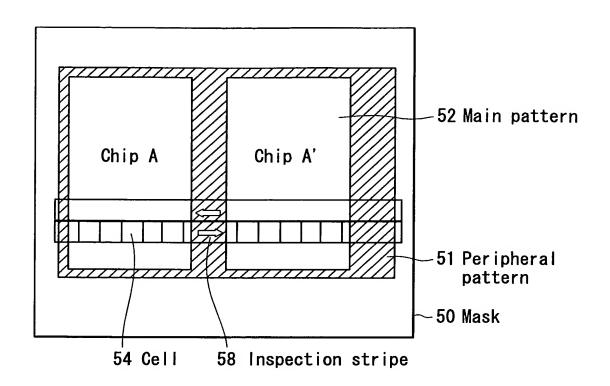


FIG. 10

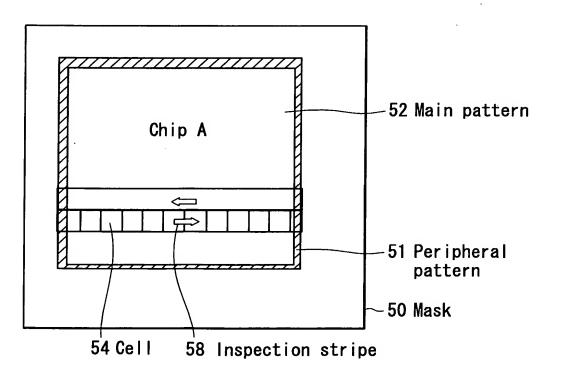


FIG. 11

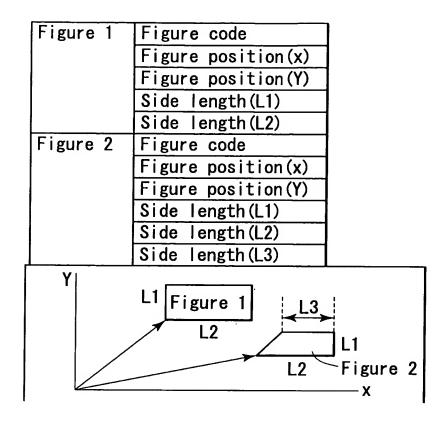


FIG. 12

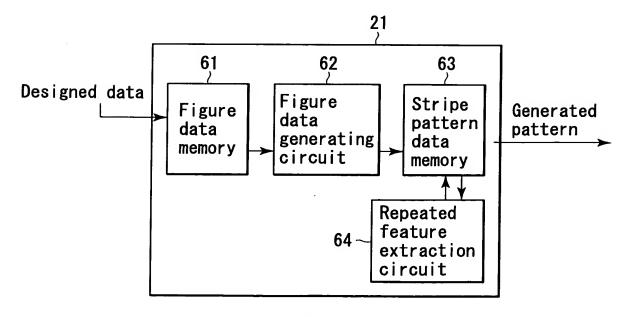


FIG. 13

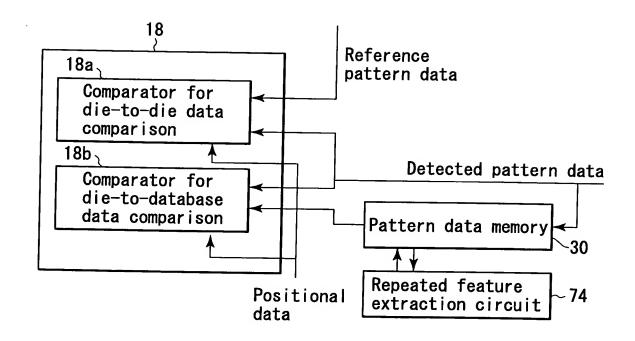


FIG. 14

